



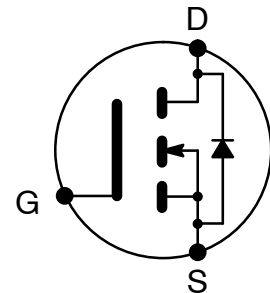
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**NTE2912  
 MOSFET  
 N-Channel, Enhancement Mode  
 High Speed Switch  
 TO220 Type Package**

**Features:**

- Advanced Process technology
- Ultra Low ON-Resistance
- Dynamic dv/dt Rating
- +175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated



**Description:**

The NTE2912 Power MOSFET utilizes advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO220 contribute to its wide acceptance throughout the industry.

**Absolute Maximum Ratings:**

Continuous Drain Current ( $V_{GS} = 10V$ ), $I_D$	
$T_C = +25^\circ C$ (Note 1) .....	82A
$T_C = +100^\circ C$ .....	58A
Pulsed Drain Current (Note 2), $I_{DM}$ .....	280A
Power Dissipation ( $T_C = +25^\circ C$ ), $P_D$ .....	230W
Linear Derating Factor .....	1.5W/ $^\circ C$
Gate-Source Voltage, $V_{GS}$ .....	$\pm 20V$
Avalanche Current (Note 2), $I_{AR}$ .....	43A
Repetitive Avalanche Energy (Note 2), $E_{AR}$ .....	23mJ
Peak Diode Recovery dv/dt (Note 3, dv/dt, $V_{DSS}$ ) .....	5.9V/ns
Operating Junction Temperature Range, $T_J$ .....	$-55^\circ$ to $+175^\circ C$
Storage Temperature Range, $T_{stg}$ .....	$-55^\circ$ to $+175^\circ C$

Note 1. Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A.

Note 2. Repetitive rating: pulse width limited by maximum channel temperature.

Note 3.  $I_{SD} \leq 43A$ ,  $di/dt \leq 300A/s$ ,  $V_{DD} \leq V_{(BR)DSS}$ ,  $T_J +175^\circ C$ .

**Absolute Maximum Ratings (Cont'd):**

Lead Temperature (During Soldering, 1.6mm from case, 10sec),  $T_L$  ..... +300°C  
 Maximum Thermal Resistance, Junction-to-Case,  $R_{thJC}$  ..... 0.65°C/W  
 Typical Thermal Resistance, Case-to-Sink (Flat, greased surface),  $R_{thCS}$  ..... 0.5°C/W  
 Maximum Thermal Resistance, Junction-to-Ambient,  $R_{thJA}$  ..... 62°C/W

**Electrical Characteristics:** ( $T_J = +25^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Drain-to-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250^\circ A$	75	-	-	V
Breakdown Voltage Temperature Coefficient	$\pm V_{(BR)DSS}/\pm T_J$	Reference to +25°C, $I_D = 1mA$	-	0.074	-	V/°C
Static Drain-to-Source On-Resistance	$R_{DS(on)}$	$V_{GS} = 10V, I_D = 43A$ , Note 5	-	-	13	m $\leq$
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250^\circ A$	2.0	-	4.0	V
Forward Transconductance	$g_{fs}$	$V_{DS} = 50V, I_D = 43A$ , Note 5	38	-	-	S
Drain-Source Leakage Current	$I_{DSS}$	$V_{DS} = 75V, V_{GS} = 0V$	-	-	25	°A
		$V_{DS} = 60V, V_{GS} = 0V, T_J = +150^\circ\text{C}$	-	-	250	°A
Gate-Source Leakage Current	$I_{GSS}$	$V_{GS} = \pm 20V$	-	-	$\pm 100$	nA
Total Gate Charge	$Q_g$	$I_D = 43A, V_{DS} = 60V, V_{GS} = 10V$	-	-	160	nC
Gate-to-Source Charge	$Q_{gs}$		-	-	29	nC
Gate-to-Drain ("Miller") Charge	$Q_{gd}$		-	-	55	nC
Turn-On Delay Time	$t_{d(on)}$		$V_{DD} = 38V, I_D = 43A, R_G = 2.5\leq, V_{GS} = 10V$ , Note 5	-	13	-
Rise Time	$t_r$	-		64	-	ns
Turn-Off Delay Time	$t_{d(off)}$	-		49	-	ns
Fall Time	$t_f$	-		48	-	ns
Internal Drain Inductance	$L_D$	Between lead, .250 (6mm) from package and center of die contact	-	4.5	-	nH
Internal Source Inductance	$L_S$		-	7.5	-	nH
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$	-	3820	-	pF
Output Capacitance	$C_{oss}$		-	610	-	pF
Reverse Transfer Capacitance	$C_{rss}$		-	130	-	pF
Single Pulse Avalanche Energy (Note 4)	$E_{AS}$	$I_{AS} = 50A, L = 370^\circ H$	-	1280 (Note 6)	340 (Note 7)	mJ

Note 2. Repetitive rating: pulse width limited by maximum channel temperature.

Note 4. Starting  $T_J = +25^\circ\text{C}$ ,  $L = 370^\circ H$ ,  $R_G = 25\leq$ ,  $I_{AS} = 43A$ ,  $V_{GS} = 10V$ .

Note 5. Pulse width  $\leq 400^\circ s$ ; duty cycle  $\leq 2\%$ .

Note 6. This is a typical value at device destruction and represents operation outside rated limits.

Note 7. This is a calculated value limited to  $T_J = +175^\circ\text{C}$ .

**Source-Drain Ratings and Characteristics:**

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Continuous Source Current (Body Diode)	$I_S$	Note 1	-	-	82	A
Pulsed Source Current (Body Diode)	$I_{SM}$	Note 2	-	-	280	A
Diode Forward Voltage	$V_{SD}$	$I_S = 43A, V_{GS} = 0V, T_J = +25^\circ\text{C}$ , Note 5	-	-	1.2	V
Reverse Recovery Time	$t_{rr}$	$T_J = +25^\circ\text{C}, I_F = 43A, di/dt = 100A/^\circ s$ , Note 5	-	100	150	ns
Reverse Recovery Charge	$Q_{rr}$		-	410	610	°C
Forward Turn-On Time	$t_{on}$	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S + L_D$ )				

Note 1. Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A.

Note 2. Repetitive rating: pulse width limited by maximum channel temperature.

Note 5. Pulse width  $\leq 400^\circ s$ ; duty cycle  $\leq 2\%$ .

